

Title (en)

SYSTEM FOR PERFORMING FAST TESTING DURING FLASH REFERENCE CELL SETTING

Title (de)

SYSTEM ZUR DURCHFÜHRUNG VON SCHNELLTESTS WÄHREND DER EINSTELLUNG VON FLASH-REFERENZZELLEN

Title (fr)

SYSTEME POUR LA REALISATION D'ESSAI RAPIDE LORS DU REGLAGE DE CELLULES DE REFERENCE DE MEMOIRE FLASH

Publication

EP 1831892 A4 20090610 (EN)

Application

EP 05848820 A 20051118

Priority

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- US 8926805 A 20050324

Abstract (en)

[origin: WO2006071402A1] An embedded circuit (14) in a memory device (10) is used in place of an external test device to perform time-consuming tasks such as voltage verification during the setting of reference cells (20). An external test device (16) programs at least one reference cell (22) to a predetermined value. The embedded circuit uses the cell (22) programmed by the external device as a comparative reference to program additional reference cells (20).

IPC 8 full level

G11C 7/14 (2006.01)

CPC (source: EP)

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Citation (search report)

- [X] US 2004130943 A1 20040708 - HIRANO YASUAKI [JP], et al
- [XA] US 5828601 A 19981027 - HOLLMER SHANE C [US], et al
- [A] US 6304485 B1 20011016 - HARARI ELIYAHOU [US], et al
- [XA] US 2004012993 A1 20040122 - KURIHARA KAZUHIRO [JP]
- See references of WO 2006071402A1

Designated contracting state (EPC)

DE FR GB

DOCDB simple family (publication)

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